Notice of References Cited Application/Control No. 10/724,789 Examiner Richard Chan Applicant(s)/Patent Under Reexamination FUTOHASHI, ICHIRO Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,947,728	09-2005	Tagawa et al.	455/414.1
	В	US-			
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	F	US-		,	
	G	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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